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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <small>(use as many sheets as necessary)</small>				Application Number	Based on SN 10/035,441
				Filing Date	Filed: January 4, 2002
				First Named Inventor	Naoski YAMAGUCHI et al.
				Group Art Unit	1765
				Examiner Name	Anita Karen Alanko
Sheet	1	of	3	Attorney Docket Number	0756-7191

<b>U.S. PATENT DOCUMENTS</b>					
Examiner Initials	Cite No. <sup>1</sup>	U.S. Patent Documents		Name of Person or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code (if known)		
CL		5,808,318		Masumo et al.	09/15/1998
		5,904,550		Yamaguchi	05/18/1999
		5,773,309		Weiner	06/30/1998
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<b>FOREIGN PATENT DOCUMENTS</b>					
Examiner Initials	Cite No. <sup>1</sup>	Foreign Patent Document		Name of Person or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Office <sup>2</sup>	Number <sup>2</sup> (if known)		
CL	JP	05-243576			09/21/1993
CL	JP	08-051078			02/20/1996
CL	JP	06-204132			07/22/1994

<b>OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS</b>					
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			
CL		F. Ueno "Observation of fast microscopic phase change phenomena of chalcogenide thin films," Japanese Journal of Applied Physics, Supplement, Vol. 26, Supplement 26-4, pp. 55-60, 1987.			
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Examiner Signature	calwona	Date Considered	6.20.05
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<sup>1</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.